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FAIRCHILD SEMICONDUCTOR®

November 2013

FQP32N20C / FQPF32N20C

N-Channel QFET® MOSFET

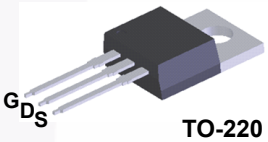
200 V, 28 A, 82 mΩ

Features

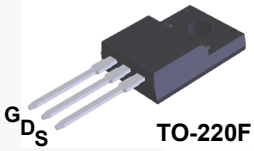
- 28 A, 200 V, $R_{DS(on)}$ = 82 mΩ (Max.) @ V_{GS} = 10 V, I_D = 14 A
- Low Gate Charge (Typ. 82.5 nC)
- Low Crss (Typ. 185 pF)
- 100% Avalanche Tested

Description

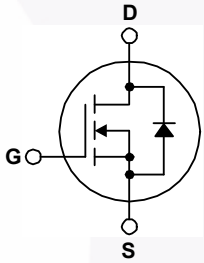
This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.



TO-220



TO-220F



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter		FQP32N20C	FQPF32N20C	Unit
V_{DSS}	Drain to Source Voltage		200		V
I_D	Drain Current	-Continuous (T_C = 25°C)	28.0	28.0 *	A
		-Continuous (T_C = 100°C)	17.8	17.8 *	A
I_{DM}	Drain Current	- Pulsed (Note 1)	112	112 *	A
V_{GSS}	Gate to Source Voltage		± 30		V
E_{AS}	Single Pulsed Avalanche Energy	(Note 2)	955		mJ
I_{AR}	Avalanche Current	(Note 1)	28.0		A
E_{AR}	Repetitive Avalanche Energy	(Note 1)	15.6		mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5		V/ns
P_D	Power Dissipation	(T_C = 25°C)	156	50	W
		- Derate above 25°C	1.25	0.4	W/°C
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150		°C
T_L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300		°C

*Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FQP32N20C	FQPF32N20C	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max	0.8	2.51	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max	62.5	62.5	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQP32N20C	FQP32N20C	TO-220	Tube	N/A	50 units
FQPF32N20C	FQPF32N20C	TO-220F	Tube	N/A	50 units

Electrical Characteristics T_C = 25°C unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_D = 250 µA	200	--	--	V
ΔBV_{DSS} / ΔT_J	Breakdown Voltage Temperature Coefficient	I_D = 250 µA, Referenced to 25°C	--	0.24	--	V/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 200 V, V_{GS} = 0 V	--	--	10	µA
		V_{DS} = 160 V, T_C = 125°C	--	--	100	µA
I_{GSSF}	Gate-Body Leakage Current, Forward	V_{GS} = 30 V, V_{DS} = 0 V	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	V_{GS} = -30 V, V_{DS} = 0 V	--	--	-100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS} = V_{GS}, I_D = 250 µA	2.0	--	4.0	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	V_{GS} = 10 V, I_D = 14 A	--	0.068	0.082	Ω
g_{FS}	Forward Transconductance	V_{DS} = 40 V, I_D = 14 A	--	20	--	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = 25 V, V_{GS} = 0 V, f = 1.0 MHz	--	1700	2220	pF
C_{oss}	Output Capacitance		--	400	520	pF
C_{rss}	Reverse Transfer Capacitance		--	185	245	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = 100 V, I_D = 32 A, R_G = 25 Ω (Note 4)	--	25	60	ns
t_r	Turn-On Rise Time		--	270	550	ns
$t_{d(off)}$	Turn-Off Delay Time		--	245	500	ns
t_f	Turn-Off Fall Time		--	210	430	ns
Q_g	Total Gate Charge	V_{DS} = 160 V, I_D = 32 A, V_{GS} = 10 V (Note 4)	--	82.5	110	nC
Q_{gs}	Gate-Source Charge		--	10.5	--	nC
Q_{gd}	Gate-Drain Charge		--	44.5	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current		--	--	28	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current		--	--	112	A
V_{SD}	Drain-Source Diode Forward Voltage	V_{GS} = 0 V, I_S = 28 A	--	--	1.5	V
t_{rr}	Reverse Recovery Time	V_{GS} = 0 V, I_S = 32 A, dI_F / dt = 100 A/µs	--	265	--	ns
Q_{rr}	Reverse Recovery Charge		--	2.73	--	µC

Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature.
2. L = 1.4 mH, I_{AS} = 32 A, V_{DD} = 50 V, R_G = 25 Ω, starting T_J = 25°C.
3. I_{SD} ≤ 28 A, di/dt ≤ 300 A/µs, V_{DD} ≤ BV_{DSS}, starting T_J = 25°C.
4. Essentially independent of operating temperature.

Typical Characteristics

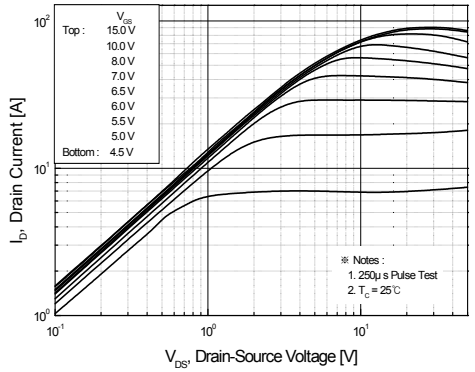


Figure 1. On-Region Characteristics

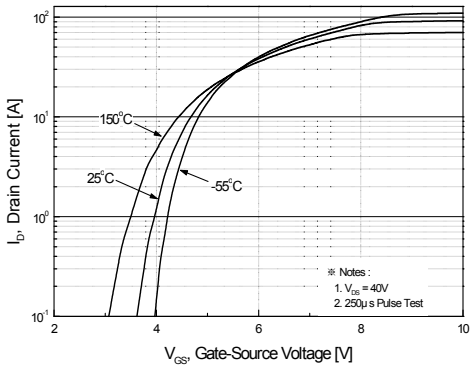


Figure 2. Transfer Characteristics

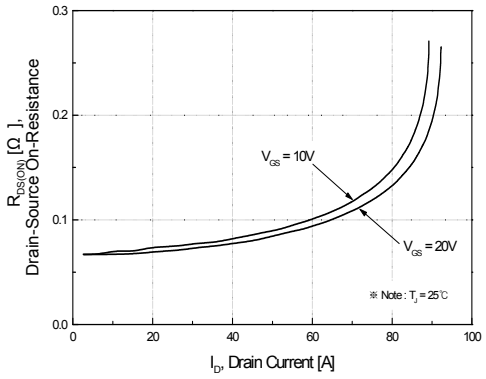


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

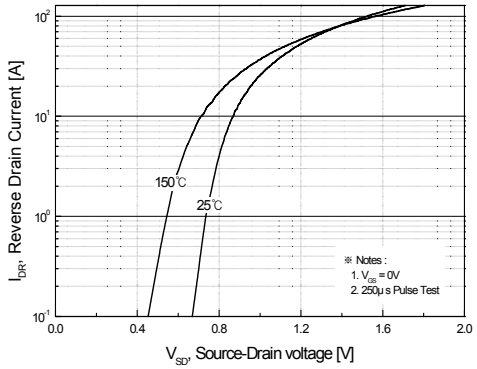


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

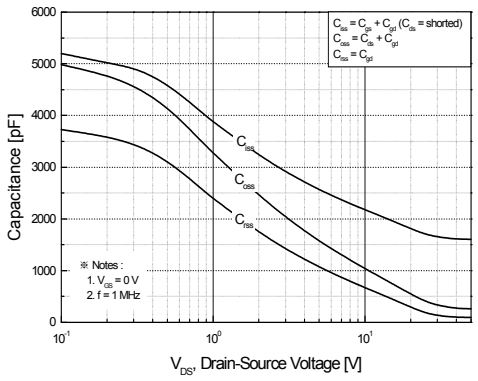


Figure 5. Capacitance Characteristics

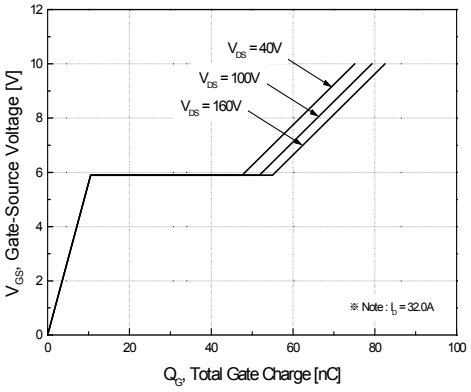


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

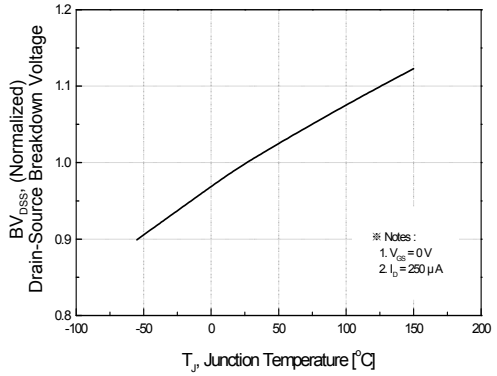


Figure 7. Breakdown Voltage Variation vs Temperature

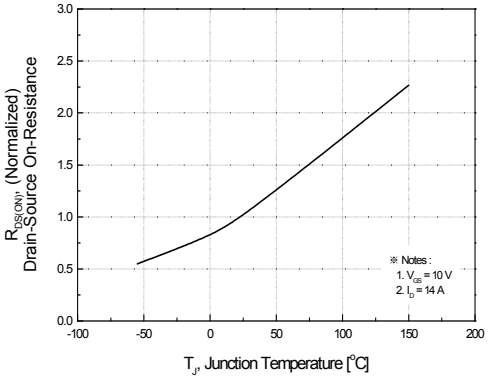


Figure 8. On-Resistance Variation vs Temperature

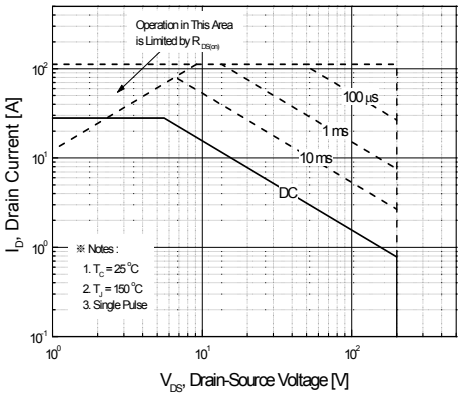


Figure 9-1. Maximum Safe Operating Area for FQP32N20C

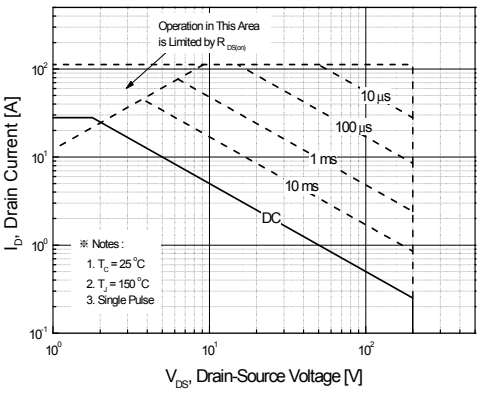


Figure 9-2. Maximum Safe Operating Area for FQPF32N20C

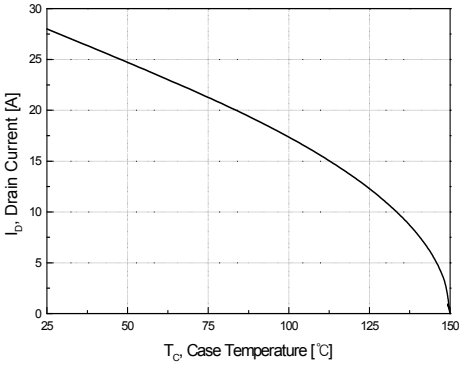


Figure 10. Maximum Drain Current vs Case Temperature

Typical Characteristics (Continued)

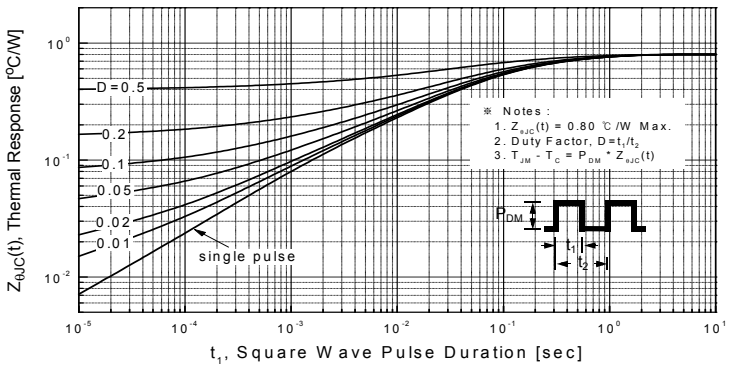


Figure 11-1. Transient Thermal Response Curve for FQP32N20C

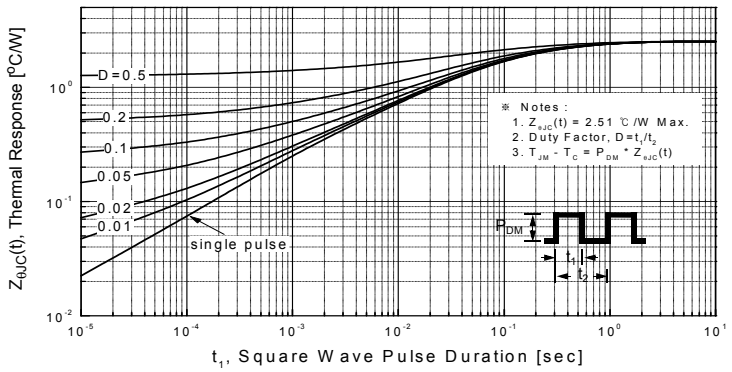


Figure 11-2. Transient Thermal Response Curve for FQPF32N20C

Figure 12. Gate Charge Test Circuit & Waveform

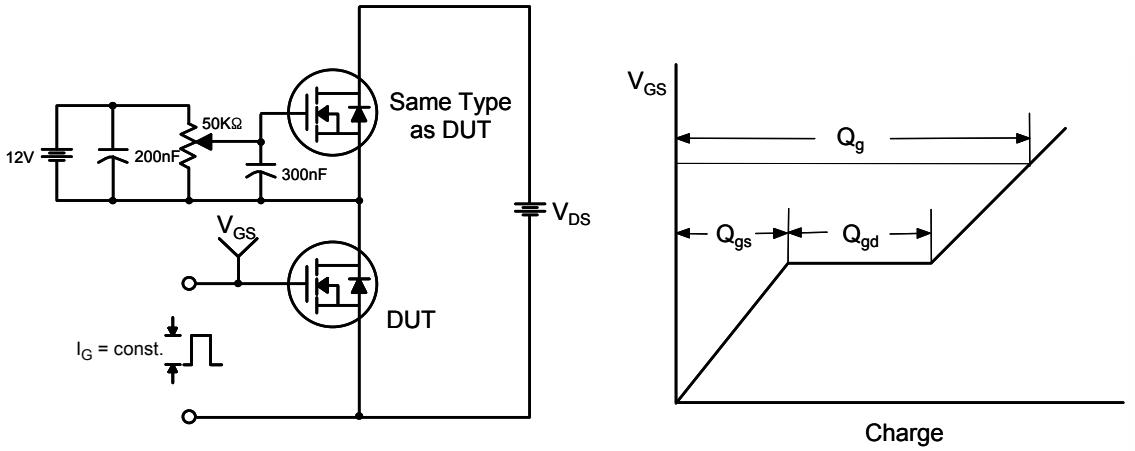


Figure 13. Resistive Switching Test Circuit & Waveforms

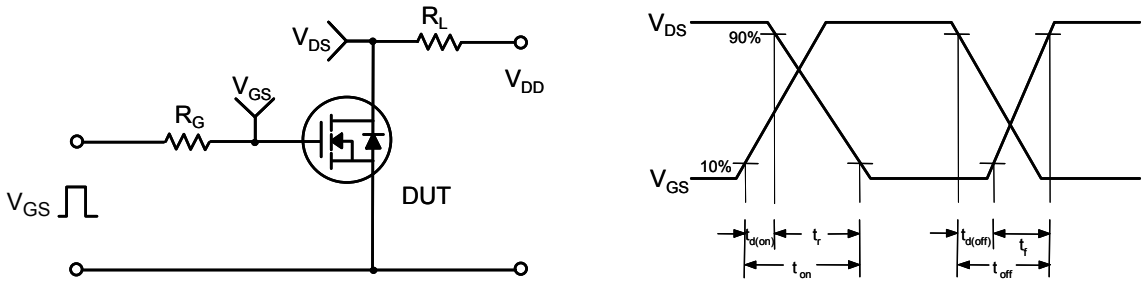


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

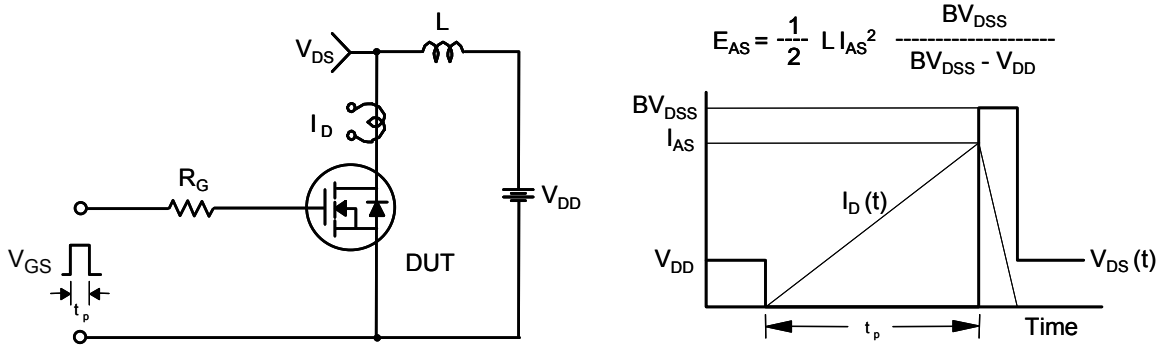
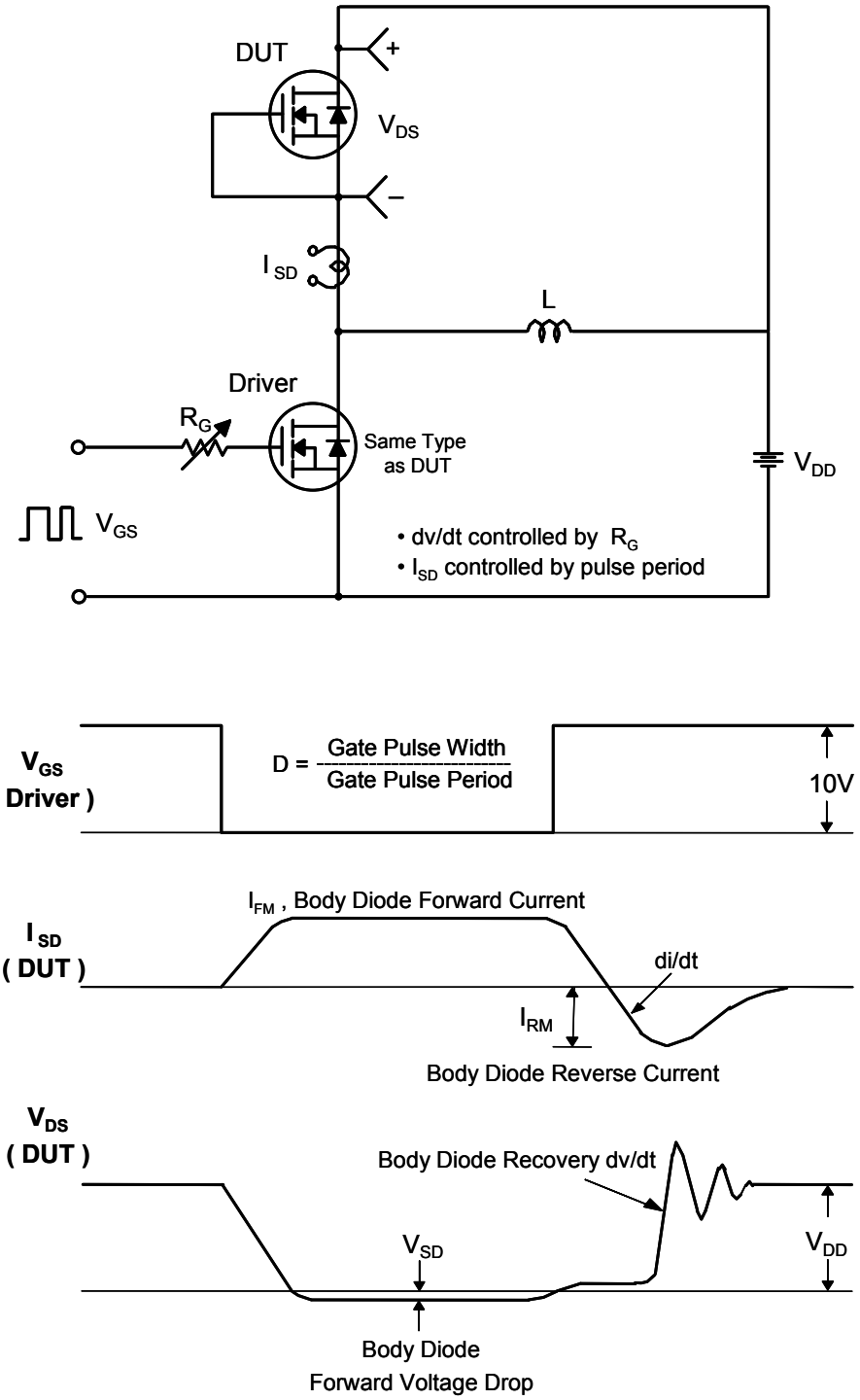


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



Mechanical Dimensions

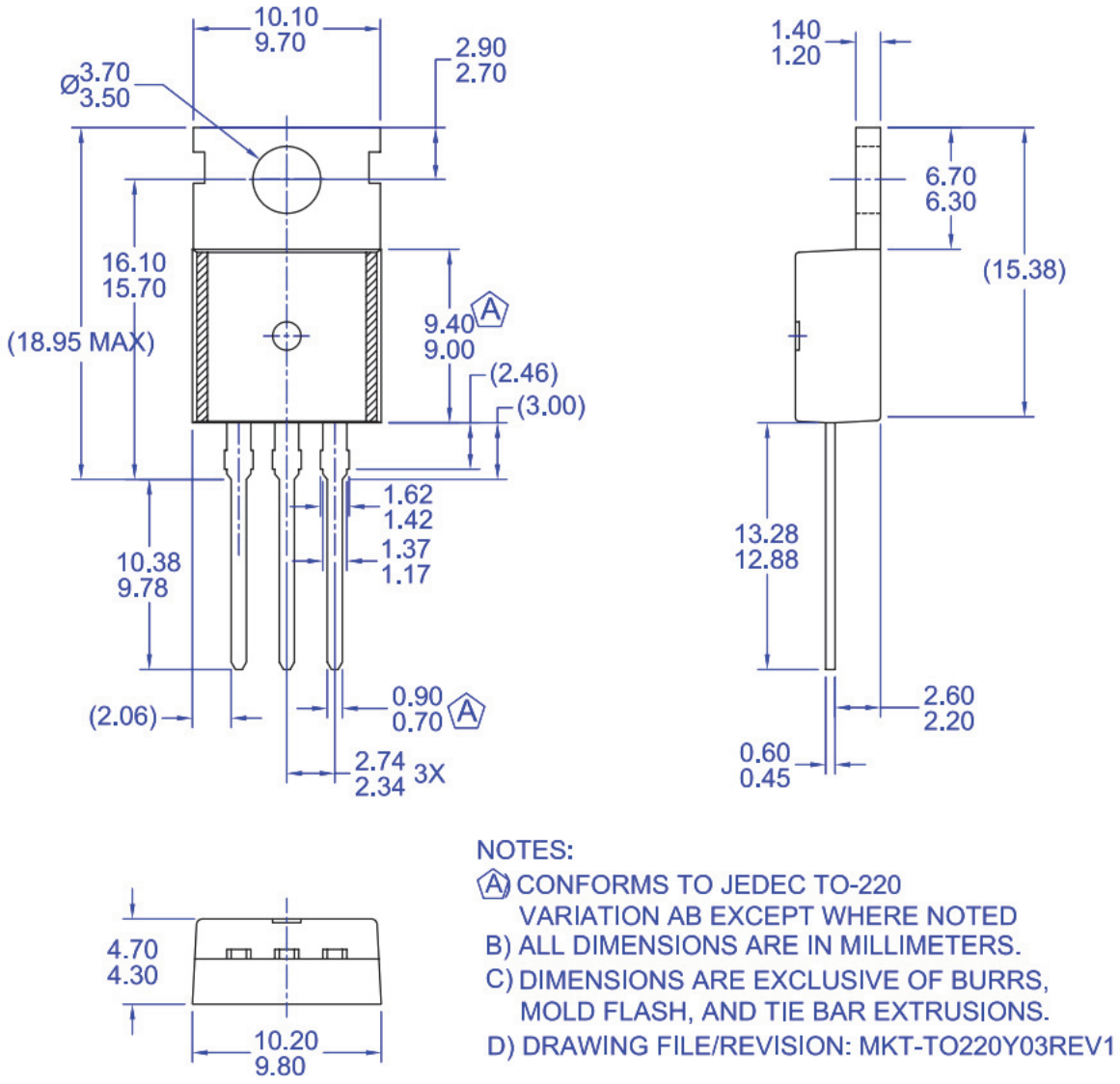


Figure 16. TO220, Molded, 3-Lead, Jedec Variation AB

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Mechanical Dimensions

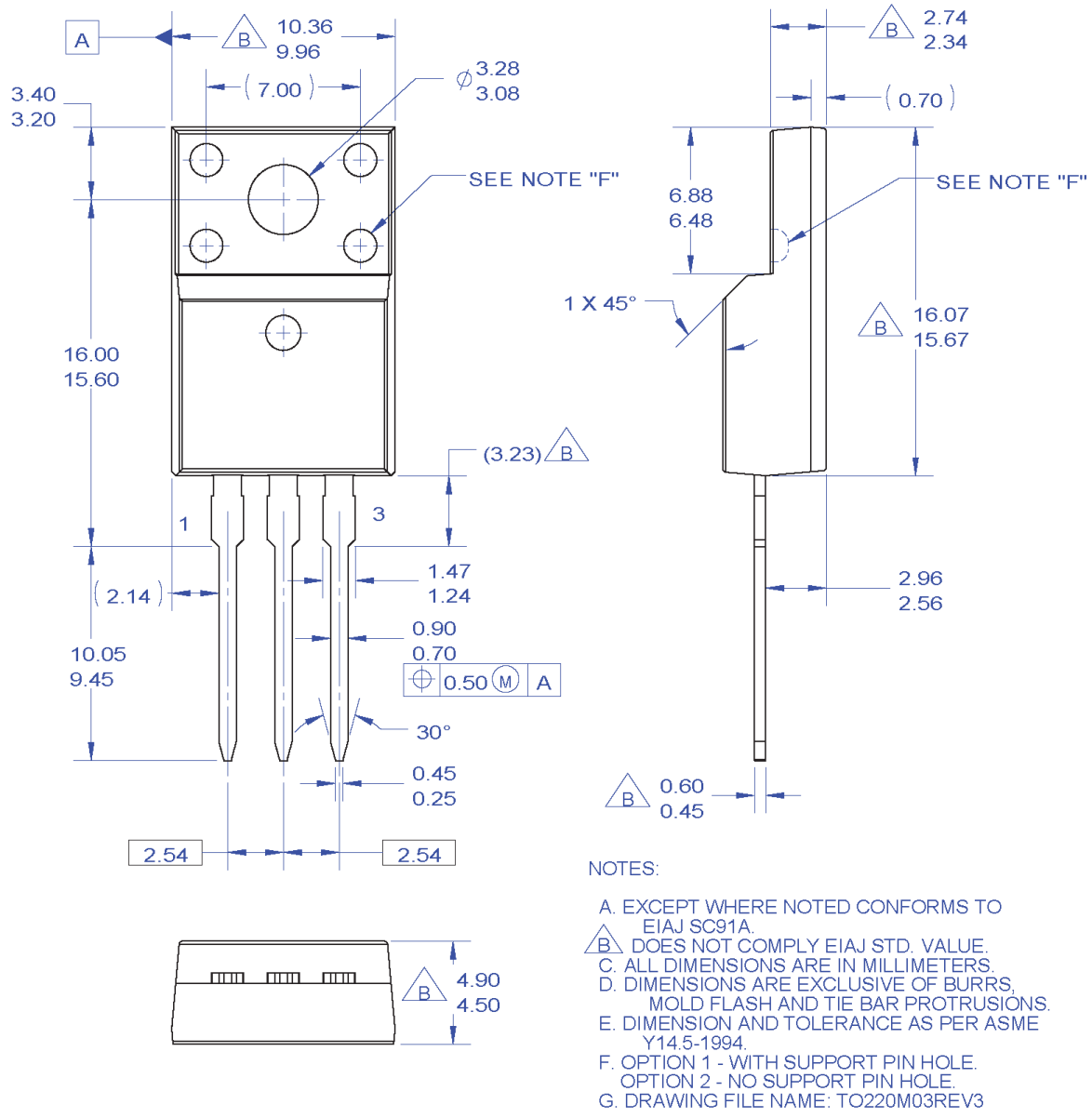

Figure 17. TO220, Molded, 3-Lead, Full Pack, EIAJ SC91, Straight Lead

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Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. I66

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